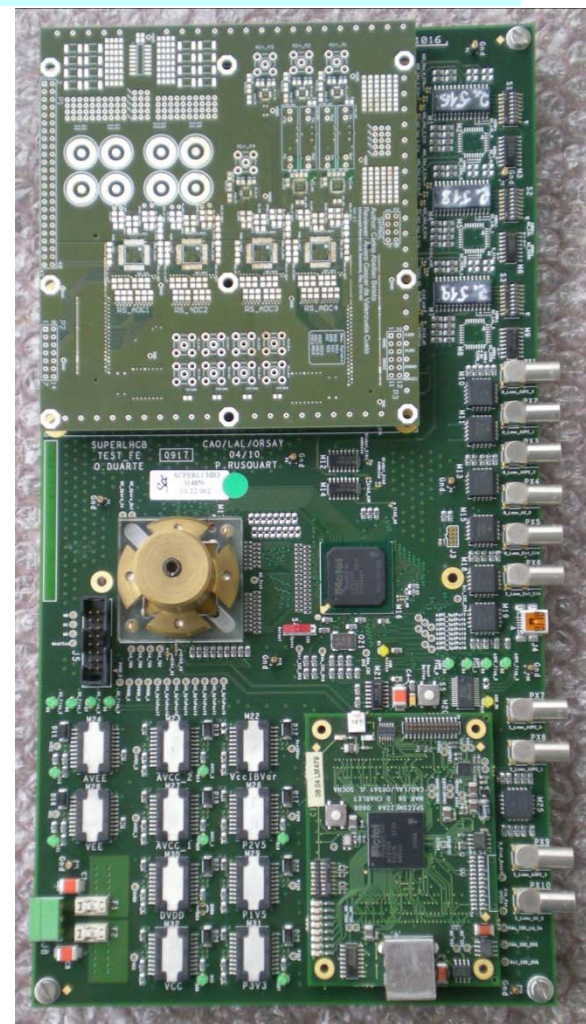


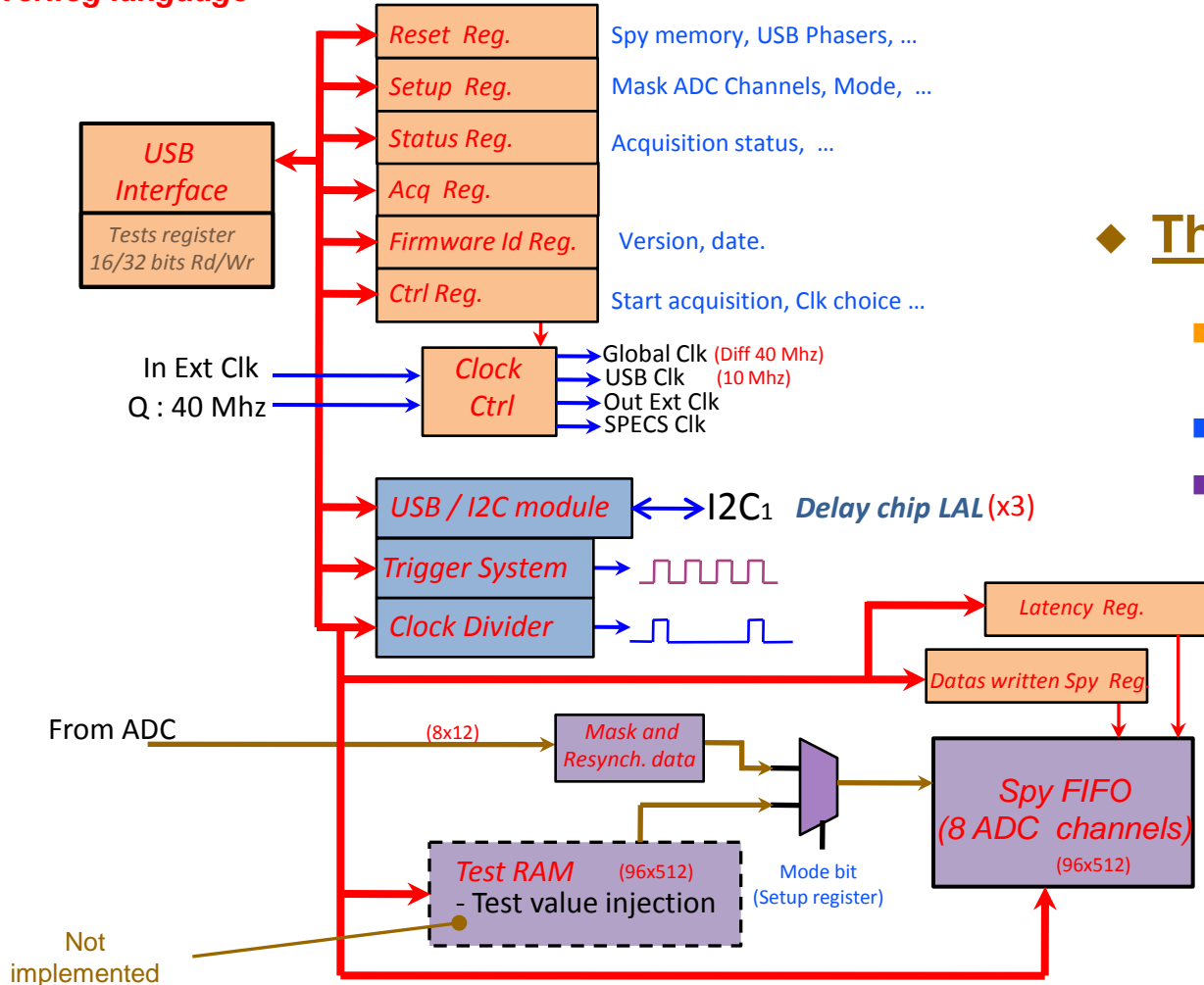
Tests Front-end card Status

- ◆ Firmware A3PE
 - Architecture status
 - Clock divider and Trigger generator
- ◆ Acquisition sequence
- ◆ Basic DAQ
- ◆ Test status
- ◆ Next step



Firmware architecture status

All Blocks inside A3PE1500
in Verilog language



◆ Three functional parts

- USB and control board
- General functionality
- DAQ

Version : 10/02/2011 18:54

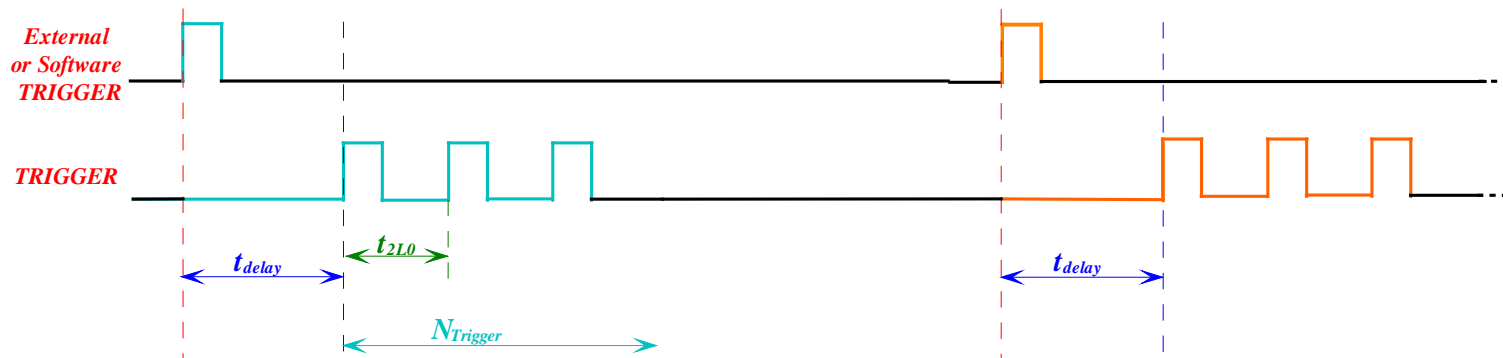
A3PE firmware blocks : Clock divider and trigger generator

◆ Clock divider

- 50 ns to 0.4s (24 bits counter)

◆ Trigger generator (L0)

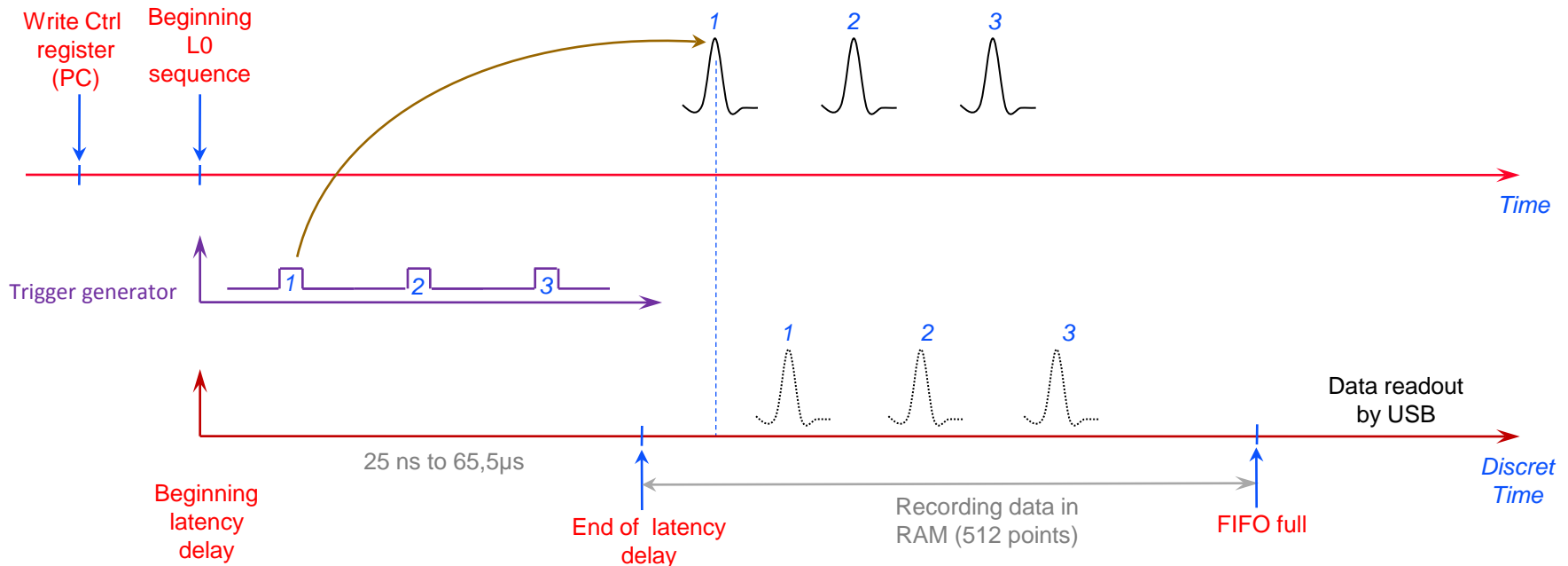
With this module we can produce trigger (external trigger or software command)



Trigger generator registers (32b) loaded by USB

{ bit[7:0] : define Tdelay
bit[23:8] : define time between 2 trigger
bit[31:24] : define trigger number

Acquisition sequence



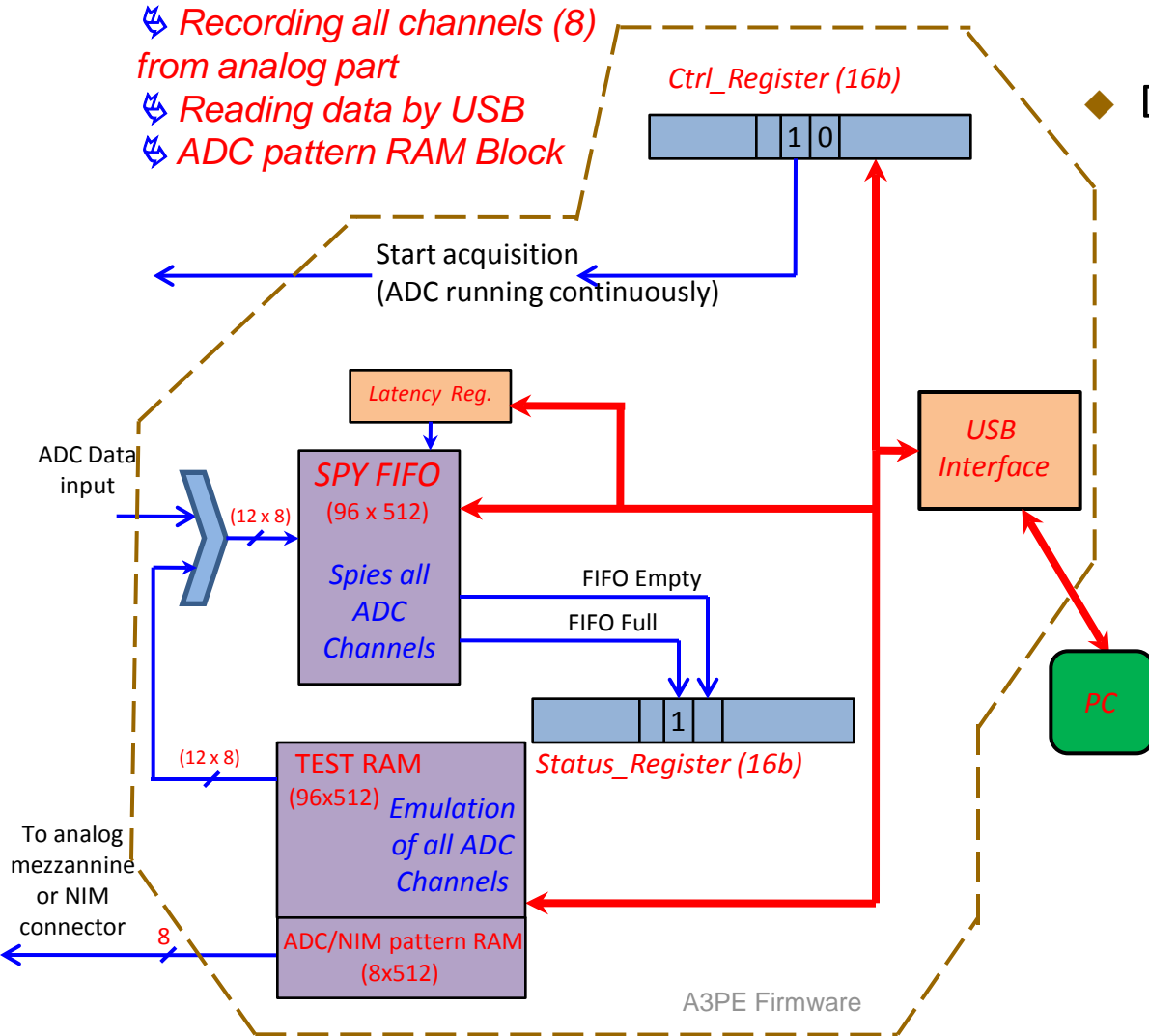
- ◆ PC write start sequence bit of Ctrl register.
- ◆ Beginning of L0 sequence.
- ◆ Each trigger pulse involve pulse shape.
- ◆ At the end of the latency delay recording 512 points of data.
- ◆ At the end of the record the system write one “end of acquisition” bit in the Status register.
- ◆ The PC scrutinize the Ctrl register, when the “end of acquisition” is high the PC download data with the USB interface.

Basic DAQ

Recording all channels (8) from analog part

Reading data by USB

ADC pattern RAM Block



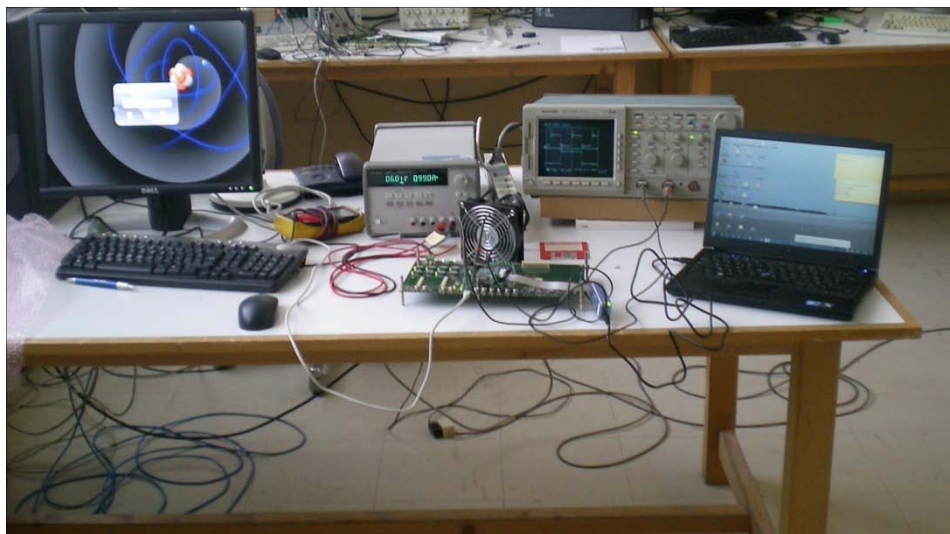
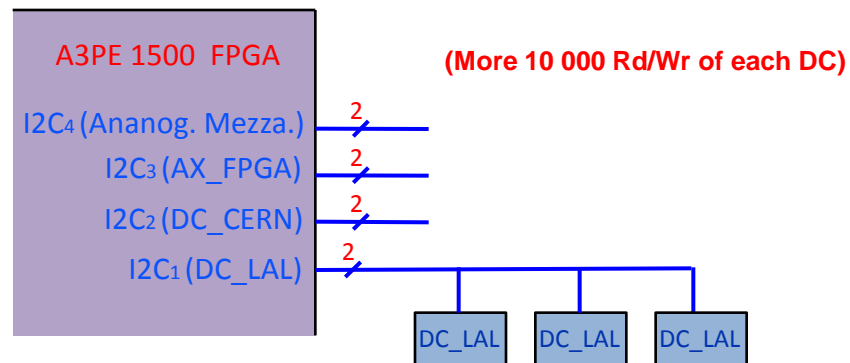
DAQ sequence

- Load RAMs sequences (Test and pattern)
- USB Interface write the start_acquisition bit in the Ctrl_Register
- ADC data are writing in FIFO
- When the FIFO is full we write FIFO_full bit in the Status_register
- The PC scrutinize the status register and when the FIFO_full bit is high the USB read the FIFO
- When the FIFO is empty we can start new acquisition

Tests Status

◆ Intensive tests with Frédéric's code

- Rd / Wr register
- Rd / Wr Spy FIFO
- I2C module (Delay Chip)
(first I2C module to drive DC_LAL)



◆ Tests with “test_245” by Chafik.

- Latency delay
- Reset tree
- ...

Next steps

End of
February

- ◆ **AX500 Basic test, before cabling 2 new board.**
- ◆ **RAM test.** *(Thierry's code)*
- ◆ **Tests trigger generator module for Lemo outputs.**
- ◆ **Intensive test of basic DAQ.**
Recording all channels (8) from analog part and read data by USB
- ◆ **Digital board for Barcelona team.**
- ◆ **Analog board for LAL team ?**



Spring /
summer

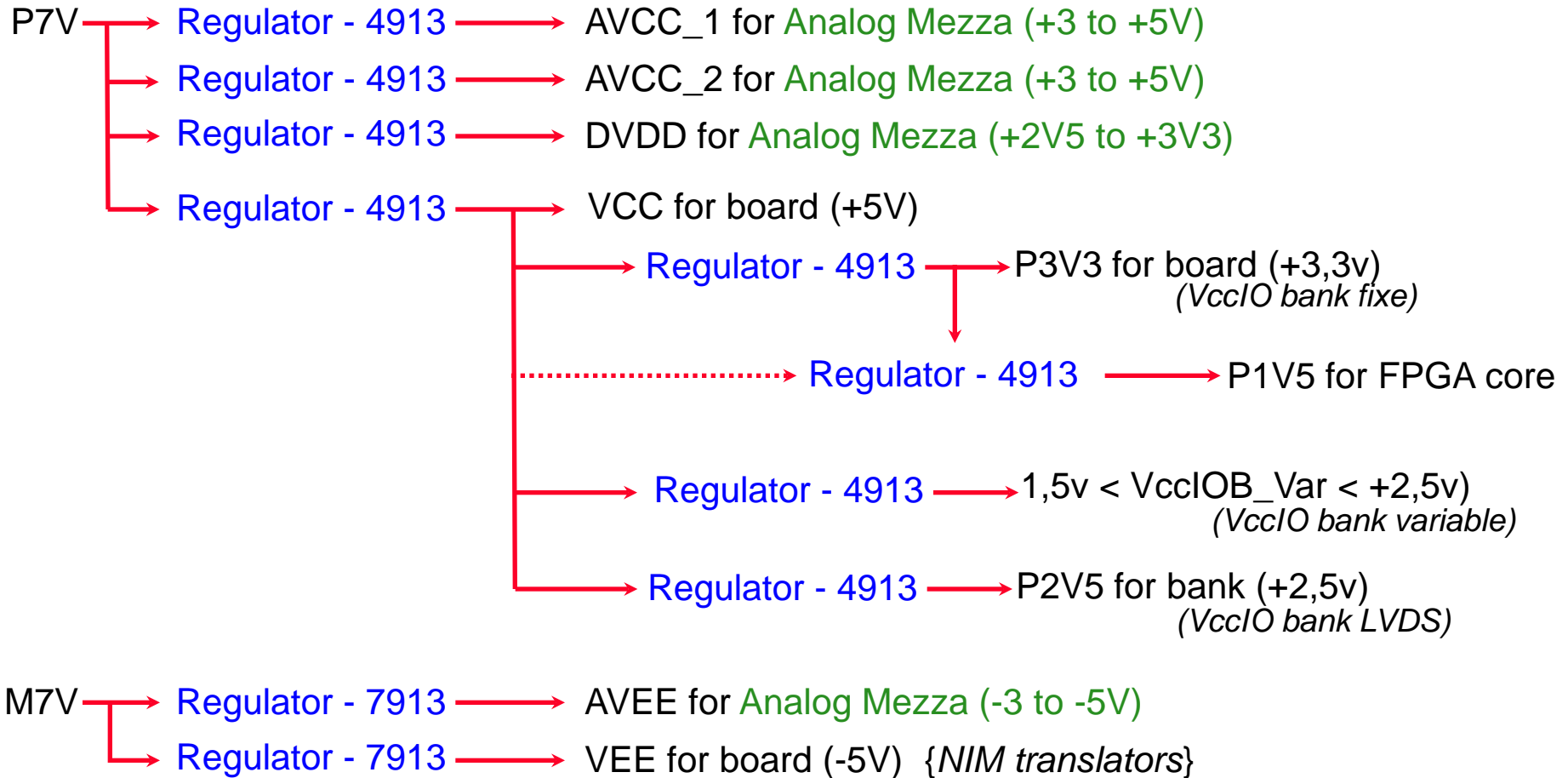
- ◆ **Processing ADC data (dynamic pedestal subtraction)**
Adaptation Christophe's code or PC computing
- ◆ **Packing**
- ◆ **A3PE FPGA tests (SS0, SSI, ...)**

Depending
accelerator
availability !

- ◆ **Radiation tests**

SPARE

Tests board power supply



- **Lab. Power Supply input (+/- 7V)**
- **10 Radiation tolerance regulators !!**

New RAM Blocks organization

